Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination NIIYA, HIROTAKA	
10/779,779		
Examiner	Art Unit	
W. Patty Chen	2871	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
349/114 combined with key words search of all databases in EAST	5/17/2006	WPC
Reviewed previously cited references	5/17/2006	WPC .
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